

PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10052255	01/23/2002	730	257	2829	CHAMBER GEYER

**APPLICANTS: Ebina Akihiko; Maruo Yutaka;

**CONTINUING DATA VERIFIED:

NONE S.B.G.

** FOREIGN APPLICATIONS VERIFIED:

JAPAN 2001-021931(P) 01/30/2001 S.B.G.

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO 111778
35 USC 119 conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no		
Verified and Acknowledged Examiners's initials		
TITLE : Method of manufacturing semiconductor integrated circuit device including nonvolatile semiconductor memory devices		

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Printed Claims
		03	03
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drawn	Figures Drawn
<input type="checkbox"/> TERMINAL DISCLAIMER		Primary Examiner PREPARED FOR ISSUE Application Examiner	
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